



सत्यमेव जयते



NABL ACCREDITED
LABORATORY No.
T0001, T1572

फार्म सं. : टी आर एफ-२००८

Form No. : TRF-2008

प्रमाणपत्र सं.

ई.क्ष.प.प्र. (उ.) ६०(४)-२०००

ERTL(N)/90(4)-2K4 / 21201

दिनांक :

Date 31 / 1 / 12

परीक्षण रिपोर्ट TEST REPORT



भारत सरकार

Government of India

संचार व सूचना प्रौद्योगिकी मंत्रालय

Ministry of Communications & Information Technology

सूचना प्रौद्योगिकी विभाग

Department of Information Technology

मानकीकरण परीक्षण एवं गुणवत्ता प्रमाणन निदेशालय

Standardisation Testing and Quality Certification Directorate

इलेक्ट्रानिकी क्षेत्रीय परीक्षण प्रयोगशाला (उत्तर)

ELECTRONICS REGIONAL TEST LABORATORY (NORTH)

(एन एस आई प्रयोगशाला आई ई सी क्यू के तहत, आई ई सी ई ई - सी वी तथा एन ए बी एल द्वारा प्रत्यापित प्रयोगशाला)

[NSI Laboratory under IECQ, IECEE-CB & NABI Accredited Laboratory]

एस-ब्लाक, ओखला औद्योगिक क्षेत्र फेज-II, नई दिल्ली ११००२०

भारत

S-Block, Okhla Industrial Area, Phase-II, New Delhi-110020

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C0001, C0177, C0178

Test Report		DATE OF RECEIPT OF ITEM	DATE OF COMPLETION OF TESTING	PAGE NO.
NUMBER	DATE			
ERTL(N)/90(4)-(2011-12)/C1201	31/01/2012	30/01/2012	31/01/2012	1 of 4
1. Service Request Form	Number	11T1106		
	Date	30/01/2012		
2. Customer	Name	M/S Power Pulse		
	Address	E-128, First Floor, Dilshad Garden Ind. Area, Delhi -110095		
3. Manufacturer	Name	M/S Power Pulse		
	Address	E-128, First Floor, Dilshad Garden Ind. Area, Delhi -110095		
4. Description of Item	Nomenclature	48 VDC /24A n+1 Telecom Power Supply		
	Make / Trade Mark	Power Pulse		
	Model No./Type No.	PP2K5-48T		
	Number of sample/ Serial No.	1/3977		
	Year of Manufacture	2011		
	Condition	Good		
5. Name & address where testing carried out (In-house/ Subcontracting /Single window service /On-site /Using Customer Facilities)	Electronics Regional Test Lab. (North), S-Block, Okhla Industrial Area, Phase-II, New Delhi-110020. (India)			
6. Applicable standard/Specification	CISPR 22 Class A			
7. Test Method/Operating Procedure	CISPR 22			
8. Environmental Conditions	Temperature	25±2°C		
	Relative Humidity	60% +/- 5%		
9. No of Annexures (If any)	02			

Tested By

Approved By

Issued by

(AU Khan)
SCIENTIST "D"

(Sulekh Chand)
Scientist "E"

(Ved Prakash)
Scientist "B"





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10. Details of major equipment used

Sl. No.	Nomenclature	Make	Model/ Type No.	Calibration Valid up to
01	Receiver	R&S	ESH3	18-10-2012
02	LISN	R&S	ESH3-Z6	01-12-2012
03	Test Receiver	R&S	ESIB 26	14-11-2012
04	Bi con antenna	EMCO	3109	24-06-2012
05	Log Periodic Antenna	EMCO	3146	24-06-2012

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11. Test Results:

Sl. No	Cl. No.	Parameter	Nominal Value/ Requirements	Measured Value/ Observations	Remarks												
1	CISPR 22	Conducted Emission Under normal Operating Condition Test Method CISPR22 ClassA	Emission Limit(Class A) <table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th>Freq .Range in MHz</th> <th colspan="2">Emission Limit dBuV</th> </tr> <tr> <td></td> <th>QP</th> <th>Avg</th> </tr> </thead> <tbody> <tr> <td>0.150-0.5</td> <td>79</td> <td>66</td> </tr> <tr> <td>5-30</td> <td>73</td> <td>60</td> </tr> </tbody> </table>	Freq .Range in MHz	Emission Limit dBuV			QP	Avg	0.150-0.5	79	66	5-30	73	60	In compliance Refer Annexure: A1-A6	Satisfactory
Freq .Range in MHz	Emission Limit dBuV																
	QP	Avg															
0.150-0.5	79	66															
5-30	73	60															
2	CISPR 22	Radiated Emission Under normal operating Condition Test method : CISPR 22 Class A Distance : 10 m	Emission Limit(Class A) <table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th>Freq .Range in MHz</th> <th>Emission Limit dBuV/m</th> </tr> <tr> <td></td> <th>Quasi Peak</th> </tr> </thead> <tbody> <tr> <td>30-230</td> <td>40</td> </tr> <tr> <td>230-1000</td> <td>47</td> </tr> </tbody> </table>	Freq .Range in MHz	Emission Limit dBuV/m		Quasi Peak	30-230	40	230-1000	47	In compliance Refer Annexure: B1-B5	Satisfactory				
Freq .Range in MHz	Emission Limit dBuV/m																
	Quasi Peak																
30-230	40																
230-1000	47																

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- Remarks:
- This report pertains to the parameters mentioned in the test results column.
 - Uncertainty in measurement has been taken into consideration while declaring the results of the parameters mentioned in the report.
 - EUT meets the requirements of the applicable standard / specification .

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